

NAV DATA SHEET

IDA Navigator (NAV™) is a thin client component of the SiGlaz Intelligent Defect Analysis (IDA), Enterprise Edition. IDA Navigator enables the user to query the IDA SQL data base to review the results of IDA analysis recipes. IDA Navigator may be used to optimize the Automation Workbench recipes, to diagnose the root cause of a process excursion and to identify trends in the inspection data over an extended period of time.

The results of a user query may be displayed for an individual wafer or for a number of wafers analyzed over an extended period of time. The user may filter the data by any wafer process variable (e.g., process step, lot ID, or wafer slot number) or by signature type. The results of the query may be displayed as a process control chart, applying WECO rules to identify various alarm conditions in the data (e.g., any point above mean plus three sigma, or two of three points above mean plus two sigma).

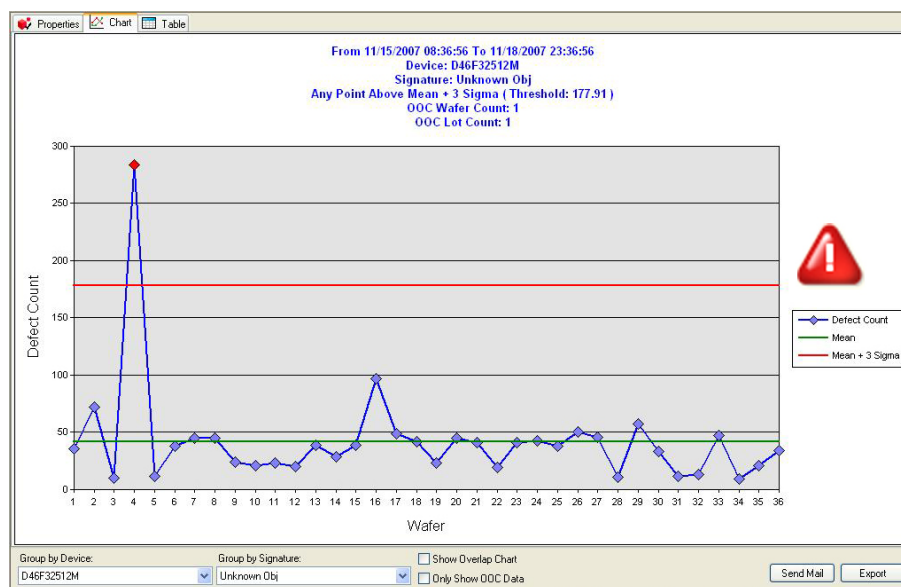


Figure 1

IDA Navigator allows the user to display the results of a query as a process control chart, applying WECO rules. The chart above shows two of three points exceeding the two sigma threshold.

In addition to the process control chart, IDA Navigator may be used to generate a signature results table. This table is a useful report to review the individual wafer results from user query. The results may also be exported to an Excel file for detailed offline review. In the Excel file, the results are sorted by signature type; there is a separate Excel worksheet for each specified defect signature type (by classification number).

The signature results table contains two thumbnail images for each signature type: one shows all of the defects on the wafer level; the second thumbnail shows only the defects of the specified signature. Wafer information (e.g., Step ID, Device ID, Lot number, wafer slot) is also displayed with the images. By reviewing the signature results table, the user can quickly validate the signatures that were identified by the IDA analysis and identify the wafers that have been affected. To view a more detailed wafer map, the user may double click on the thumbnail.

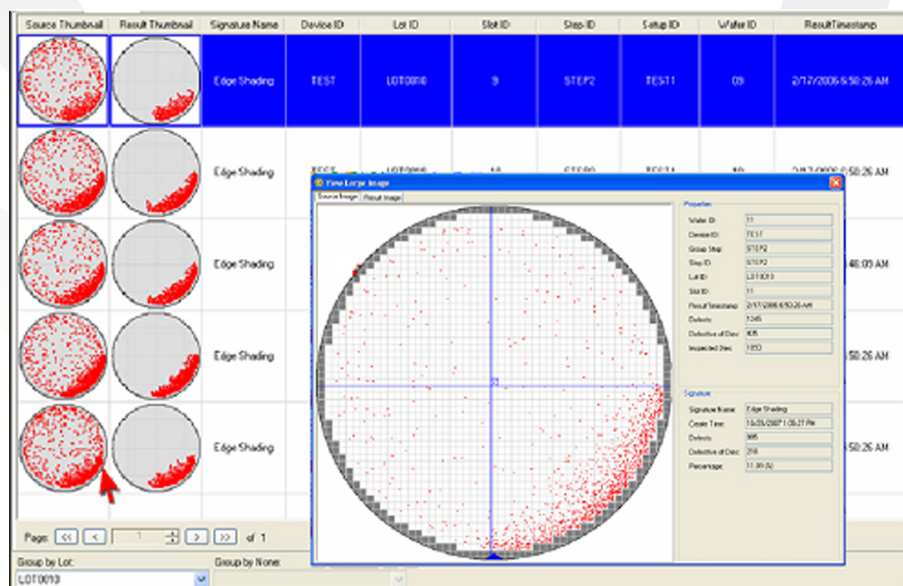


Figure 2

*IDA allows the user to display a signature results table that shows all occurrences of a signature that meet the query conditions.
The user may display a detailed wafer map by clicking on the thumbnail*

To generate the data base for IDA Navigator, the user includes a functional block in the AWB analysis recipe that writes the WIP information (Lot ID, Slot ID, etc) and the signature information to a Microsoft SQL data base running on the server. The recipe generates a separate record in the data base for each signature type (classification number) identified on the wafer.

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